

(19) World Intellectual Property Organization  
International Bureau



(43) International Publication Date  
27 February 2003 (27.02.2003)

PCT

(10) International Publication Number  
**WO 03/016843 A1**

(51) International Patent Classification<sup>7</sup>: **G01J 3/453**,  
3/28, G02B 21/26

(21) International Application Number: **PCT/GB02/03811**

(22) International Filing Date: **19 August 2002 (19.08.2002)**

(25) Filing Language: **English**

(26) Publication Language: **English**

(30) Priority Data:  
0120170.6 17 August 2001 (17.08.2001) **GB**

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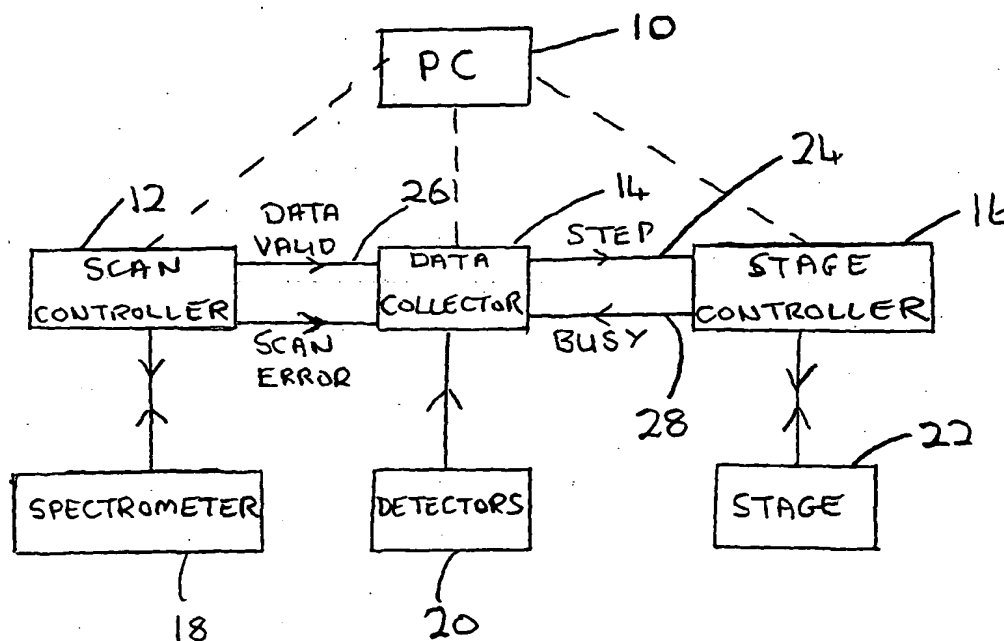
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(81) Designated States (*national*): AE, AG, AL, AM, AT, AU,  
AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU,  
CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH,  
GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC,  
LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW,  
MX, MZ, NO, NZ, OM, PH, PL, PT, RO, RU, SD, SE, SG,  
SI, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ,  
VC, VN, YU, ZA, ZM, ZW.

(84) Designated States (*regional*): ARIPO patent (GH, GM,  
KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW),  
Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM),  
European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE,  
ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE, SK,

[Continued on next page]

(54) Title: **SYSTEM AND METHOD FOR SCANNING IR MICROSCOPY**



(57) Abstract: An FT-IR microscope is operated in association with a scanning spectrometer in such a way that incremental movement of the movable stage of the microscope is synchronised with the scanning spectrometer. This minimises delays in processing time.